

Process Change Notice #1205091

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PCN Date: 5/9/2012		Effective Date: 8/15	/2012				
Title: C8051F92x/93x Revision F Transition							
Originator: Jesse Debruin	Phon	e: 512-532-5313	Dept: Product Marketing				
Customer Contact: Kathy Haggar	Phon	e: 512.532.5261	Dept: Sales				
PCN Type:							
□ Datasheet □ Foul □ Toul □ Toul	ndry		Packing				
	embly		Labeling				
☐ Discontinuance ☐ Test			Other				
Last Order Date: N/A							
PCN Details							
Description of Change:							
Silicon Labs is pleased to announce revision F of the C8051F92x/F93x devices and version 1.3							
of the corresponding datasheet for these products.							
Reason for Change:							
Revision F of the products allows customers to exceed the maximum VBAT ramp time, if							
desired, during external reset on the devi	ice.						
The datasheet includes undates to Table 4.4 Deset Floatrical Characteristics for additional							
The datasheet includes updates to Table 4.4 Reset Electrical Characteristics for additional clarification on VBAT ramp time under different operating modes along with other minor edits.							
Impact on Form, Fit, Function, Quality, Reliability:							
There is no impact to form, fit, quality or reliability. The functional change is optional as							
described.		,	3				



SILICON LABS	Process Change Notice #1205091
Duradical Identification	
Product Identification: The following ordering part numbers are at	factod:
C8051F920-F-GM	
C8051F920-F-GQ	
C8051F920-GM	
C8051F920-GQ	
C8051F921-F-GM	
C8051F921-GM	
C8051F928-GQ	
C8051F929-GQ	
C8051F930-F-GDI	
C8051F930-F-GM	
C8051F930-F-GQ	
C8051F930-GDI	
C8051F930-GM	
C8051F930-GQ	
C8051F930-GW	
C8051F930-W	
C8051F931-F-GM	
C8051F931-GM	
C8051F938-GQ	
C8051F939-GQ	
│	customer parts made from the above listed base parts
as well as tape and reel.	castomer parte made nom and above noted base parte

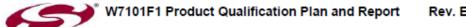


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Last Date of Unchange	ed Product: 8/15/2012
Customer Early Accep	otance Sign Off:
Customers may appro	ove early PCN acceptance by completing the information below:
Early Acceptance:	Date:
	Name:
	Company:
Email your early Acce	eptance approval to: <u>katherine.haggar@silabs.com</u>
Qualification Data:	
Please see Appendix A	ı.



Appendix A C8051F92x/3x Qualification Report



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C8051F92x/3x Rev F, TSMC Fabrication, Unisem/SPIL Assembly except as noted							
				Fatt/Pass or			
Test Name	Test Condition	Qualification	Start	End	Notes	Summary	Status
Test Group A - Ac	celerated Environment Stres	s Tests					
HAST			Q25565	0/80	1		
		3 lots, N=>25	Q25562	0/80	1		
	JA110		Q25572	0/80	2		
	130°C, 85%RH		Q25669	0/80	2		
	Vcc=3.6V, 96 hours		Q25017	0/80	3		
			Q25183	0/80	3	7 lots	
			Q25536	0/80	3	0/560	Pass
Temp Cycle			Q25560	0/80	1		
	JA104	3 lots, N=>25	Q25564	0/80	1		
	Cond C: -65°C to 150°C		Q25574	0/80	2		
	500 cycles		Q25665	0/80	2		
			Q25000	0/80	3		
			Q25185	0/80	3	7 lots	
			Q25534	0/80	3	0/560	Pass
HTSL	JA103		Q25566	0/80	1		
	150°C, 1000hr	3 lots, N=>25	Q25563	0/80	1		
			Q25573	0/80	2		
			Q25663	0/80	2		
			Q24921	0/80	3		
			Q25137	0/80	3	7 lots	
			Q25414	0/80	3	0/560	Pass
Unbiased HAST	JA118		Q24461	0/80	1		
	130°C, 85%RH, 96 hours	3 lots, N=>25	Q25571	0/80	1		
			Q25567	0/80	2		
			Q25667	0/80	2		
			Q24999	0/80	3		
			Q24184	0/80	3	7 lots	
			Q25535	0/80	3	0/560	Pass



C8051F92x/3x Qualification Report

W7101F1 Product Qualification Plan and Report Rev. E

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C8051F92x/3x Rev F, TSMC Fabrication, Unisem/SPIL Assembly except as noted							
Lot ID or Fail/Pass or							
Test Name		Qualification	Start	End	Notes	Summary	Status
Test Group B - Accel	erated Lifetime Simulation '	Tests - Unisem /	Assembly u	nless notes			
HTOL	JA108		Q25551	0/80			
	125°C, Dynamic	3 lots, N=>77	Q26146	0/80	4	3 lots	
	Vcc=1.4V for 1000 hours		Q26266	0/80		0/240	Pass
LTOL	JA108						
	-10°C, Dynamic	1 lot, N=>32	Q25548	0/40	4	1 lots	
	Vcc=3.6V, 1000 hours					0/40	Pass
ELFR	JA108		Q25505	0/500			
	125°C, Dynamic	3 lots, N=>500	Q26046	0/500			
	Vcc=3.6V, 48 hours		Q26216	0/528		4 lots	
			Q32063	0/520	5	0/1520	Pass
High Temperature	JESD22-A1117		Q26232	0/40			
Date Retention /	500 cycles @ Vcc=1.4V	3 lots, N≥39	Q26231	0/40			
Cycling Endurance	88/130°C for 500 hours		Q26235	0/40		3 lots	
for NVM						0/120	Pass
Low Temperature	JESD22-A108		Q26233	0/40			
Data Retention /	500 cycles @ Vcc=1.4V	3 lots, N≥38	Q26230	0/40			
Cycling Endurance	25°C for 500 hours		Q26234	0/40		3 lots	
for NVM						0/120	Pass
Test Group E - Electr	ical Verification						
ESD-HBM	JA114						
	ŀ	1 lot, N=>3	Q26025	0/3		2000V	Pass
			Q32061	0/3	5		
ESD-MM	JA115	4 let N - 2	02/275	0./2		225V	_
		1 lot, N=>3	Q26275	0/3		2250	Pass
ESD-CDM	JC101						
LJU-CUM	I	1 lot, N=>3	Q26237	0/3			Pass
		,	Q32062	0/3	5	1000V	
Latch Up	JESD78						
	±200mA	1 lot, N=>6	Q25523	0/6	1	85°C	
			Q25524	0/6	1	25C°	
			Q32120	0/6	5	85°C	
			Q32119	0/6	5	25C°	Pass

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C8051F92x/3x Rev F, TSMC Fabrication, Unisem/SPIL Assembly except as noted							
Test Name	Test Condition	Qualification	Start	End	Notes	Summary	Status
Supplemental P	ackage Qualification Data						
Test Group A - A	ccelerated Environment Stress	Tests - ASECL - (QFN				
HAST	JA110		Q29385	0/78		П	
	130°C, 85%RH	3 lots, N=>25	Q29331	0/80		3 lots	Pass
	96 hours		Q29336	0/80		0/238	
Temp Cycle	JA104		Q29387	0/77			
	Cond C: -65°C to 150°C	3 lots, N=>25	Q29391	0/77		3 lots	Pass
	500 cycles		Q29395	0/77		0/231	
HTSL	JA103		Q29388	0/77			
	150°C, 1000hr	3 lots, N=>25	Q29392	0/77		3 lots	Pass
			Q29396	0/77		0/231	
Test Group A - A	ccelerated Environment Stress	Tests - UNISEM -	QFN				
HAST	JA110		Q26130	0/80		П	
	130°C, 85%RH	3 lots, N=>25	Q26179	0/80		3 lots	Pass
	96 hours		Q26439	0/80		0/240	
Temp Cycle	JA104		Q26129	0/80			
	Cond C: -65°C to 150°C	3 lots, N=>25	Q26182	0/80		3 lots	Pass
	500 cycles		Q26441	0/100		0/260	
HTSL	JA103		Q26131	0/84			
	150°C, 1000hr	3 lots, N=>25	Q26180	0/85		3 lots	Pass
			Q26440	0/101		0/270	

Notes:

- 1. SPIL 32LQFP, Precond MSL3@260C
- 2. SPIL 48TQFP, Precond MSL2@260C
- 3. SPIL 64 TQFP, Precond MSL3@260C
- 4. Qualification performed on Carsem 32QFN
- 5. Die revision F

This report applies to the following part numbers:					
C8051F920-F-GM C8051F920-F-GQ	C8051F920-GQ C8051F921-F-GM	C8051F930-F-GM C8051F930-F-GQ	C8051F930-GQ C8051F931-F-GM		
C8051F920-GM	C8051F921-GM	C8051F930-GM	C8051F931-GM		